Hybrid Field Stop Trench IGBT

650 V, 75 A, TO247

AFGHL75T65SQDC

Using the novel field stop 4th generation IGBT technology and the 1.5th generation SiC Schottky Diode technology, AFGHL75T65SQDC offers the optimum performance with both low conduction and switching losses for high efficiency operations in various applications, especially totem pole bridgeless PFC and Inverter.

Features

- Maximum Junction Temperature: $T_J = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage: $V_{CE(Sat)} = 1.6 \text{ V (Typ.)} @ I_C = 75 \text{ A}$
- 100% of the Parts are Tested for I_{LM} (Note 2)
- Fast Switching
- Tight Parameter Distribution
- No Reverse Recovery/No Forward Recovery
- AEC-Q101 Qualified and PPAP Capable

Typical Applications

- Automotive
- On & Off Board Chargers
- DC-DC Converters
- PFC
- Industrial Inverter

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-to-Emitter Voltage	V _{CES}	650	V
Gate-to-Emitter Voltage Transient Gate-to-Emitter Voltage	V _{GES}	±20 ±30	V
	I _C	80 75	Α
Pulsed Collector Current (Note 2)	I _{LM}	300	Α
Pulsed Collector Current (Note 3)	I _{CM}	300	Α
Diode Forward Current (Note 1) @ $T_{C=}$ 25°C @ $T_{C=}$ 100°C	I _F	35 20	Α
Pulsed Diode Maximum Forward Current	I _{FM}	200	Α
	P _D	375 188	W
Operating Junction / Storage Temperature Range	T _J , T _{STG}	-55 to +175	°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 10 seconds	T _L	265	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

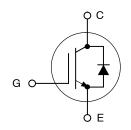
- 1. Value limited by bond wire
- 2. V $_{CC}$ = 400 V, V $_{GE}$ = 15 V, I $_{C}$ = 300 A, R $_{G}$ = 15 $\Omega,$ Inductive Load, 100% of the Parts are Tested.
- 3. Repetitive Rating: pulse width limited by max. Junction temperature



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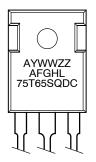
www.onsemi.com

75 A, 650 V V_{CESat} = 1.6 V (Typ.)





MARKING DIAGRAM



A = Assembly Location YWW = 3-Digit Date Code

ZZ = 2-Digit Lot Traceability Code

AFGHL75T65SQDC = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
AFGHL75T65SQDC	TO-247-3L	30 Units / Rail

THERMAL CHARACTERISTICS

Rating	Symbol	Max	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ hetaJC}$	0.4	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ hetaJC}$	1.55	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS			•	•		
Collector-emitter breakdown voltage, gate-emitter short-circuited	V _{GE} = 0 V, I _C = 1 mA	BV _{CES}	650	_	_	V
Temperature Coefficient of Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	-	0.6	-	V/°C
Collector-emitter cut-off current, gate-emitter short-circuited	V _{GE} = 0 V, V _{CE} = 650 V	I _{CES}	-	-	250	μΑ
Gate leakage current, collector-emitter short-circuited	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	-	_	±400	nA
ON CHARACTERISTICS						-
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$, $I_C = 75 \text{ mA}$	V _{GE(th)}	3.4	4.9	6.4	V
Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 75 A V _{GE} = 15 V, I _C = 75 A, T _J = 175°C	V _{CE(sat)}	- -	1.6 2.0	2.1 -	V
DYNAMIC CHARACTERISTICS						
Input capacitance	V _{CE} = 30 V,	C _{ies}	_	4574	_	pF
Output capacitance	V _{GE} = 0 V, f = 1 MHz	C _{oes}	_	289.4	_	
Reverse transfer capacitance		C _{res}	_	11.2	_	
Gate charge total	V _{CE} = 400 V,	Qg	_	139	_	nC
Gate-to-emitter charge	I _C = 75 A, V _{GE} = 15 V	Q _{ge}	_	25	_	1
Gate-to-collector charge		Q_{gc}	-	33	-	1
SWITCHING CHARACTERISTICS, INDUC	TIVE LOAD					
Turn-on delay time	T _C = 25°C,	t _{d(on)}	_	22.4	_	ns
Rise time	$V_{CC} = 400 \text{ V},$ $I_{C} = 37.5 \text{ A},$	t _r	-	19.2	-	
Turn-off delay time	$R_G = 4.7 \Omega$, $V_{GE} = 15 V$,	t _{d(off)}	-	116.8	-	1
Fall time	Inductive Load	t _f	_	9.6	_	1
Turn-on switching loss		E _{on}	-	0.48	-	mJ
Turn-off switching loss	1	E _{off}	_	0.24	_	1
Total switching loss		E _{ts}	_	0.72	_	
Turn-on delay time	T _C = 25°C,	t _{d(on)}	_	24	_	ns
Rise time	$V_{CC} = 400 \text{ V}, \\ I_C = 75 \text{ A}, \\ R_G = 4.7 \Omega, \\ V_{GE} = 15 \text{ V}, \\ \text{Inductive Load}$	t _r	_	49.6	_	1
Turn-off delay time		t _{d(off)}	_	107.2	-	1
Fall time		t _f	_	70.4	-	1
Turn-on switching loss		E _{on}	-	1.68	-	mJ
Turn-off switching loss		E _{off}	-	1.11	-	1
Total switching loss	1	E _{ts}	_	2.79	-	1

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS, IND	UCTIVE LOAD	•		•	•	
Turn-on delay time	T _C = 175°C,	t _{d(on)}	_	20.8	-	ns
Rise time	V _{CC} = 400 V, I _C = 37.5 A,	t _r	-	22.4	-	1
Turn-off delay time	$R_G = 4.7 \Omega,$ $V_{GE} = 15 V,$	t _{d(off)}	-	130	-	1
Fall time	Inductive Load	t _f	-	9.6	-	1
Turn-on switching loss		E _{on}	_	0.53	_	mJ
Turn-off switching loss		E _{off}	-	0.44	-	1
Total switching loss		E _{ts}	_	0.98	_	1
Turn-on delay time	T _C = 175°C,	t _{d(on)}	_	24	-	ns
Rise time	$V_{CC} = 400 \text{ V},$ $I_{C} = 75 \text{ A},$	t _r	_	49.6	_	1
Turn-off delay time	$R_G = 4.7 \Omega$, $V_{GE} = 15 V$,	t _{d(off)}	_	118	_	1
Fall time	Inductive Load	t _f	_	78.4	_	1
Turn-on switching loss		E _{on}	_	1.76	_	mJ
Turn-off switching loss		E _{off}	-	1.42	-	1
Total switching loss		E _{ts}	_	3.19	-	1
DIODE CHARACTERISTICS						
Forward Voltage	I _F = 20 A	V _F	_	1.45	1.75	V
	I _F = 20 A, T _J = 175°C		_	1.80	-	1
Total Capacitance	V _R = 400 V, f = 1 MHz	С	-	110	-	pF
	V _R = 400 V, f = 1 MHz		_	105	-	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

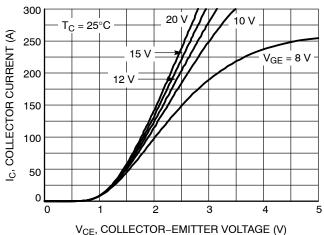
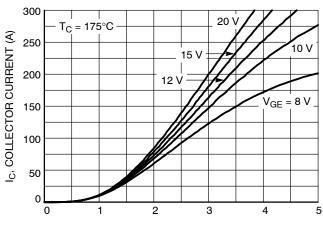
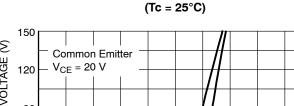


Figure 1. Typical Output Characteristics



V_{CE}, COLLECTOR-EMITTER VOLTAGE (V) Figure 2. Typical Output Characteristics



V_{GE}, GATE-EMITTER VOLTAGE (V) 90 60 30 $T_C = 25^{\circ}C$ T_C = 175°C 0 10

IC, COLLECTOR CURRENT (A) Figure 3. Transfer Characteristics

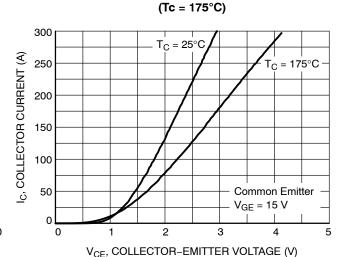


Figure 4. Typical Saturation Voltage Characteristics

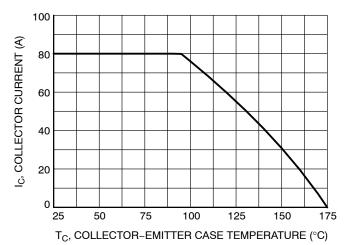
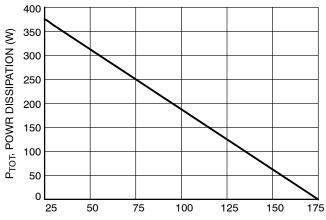


Figure 5. Collector Current Derating



T_C, COLLECTOR-EMITTER CASE TEMPERATURE (°C)

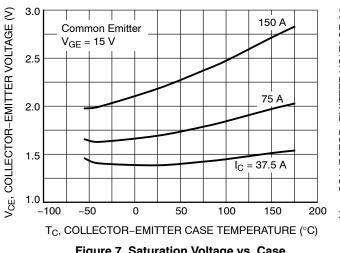


Figure 7. Saturation Voltage vs. Case Temperature at Variant Current Level

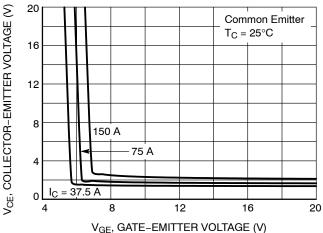


Figure 8. Saturation Voltage vs. VGE $(Tc = 25^{\circ}C)$

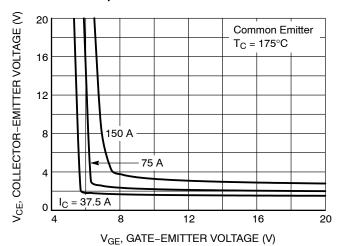


Figure 9. Saturation Voltage vs. VGE $(Tc = 175^{\circ}C)$

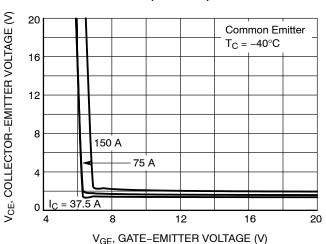


Figure 10. Saturation Voltage vs. VGE (Tc = -40° C)

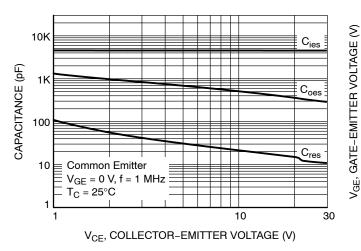


Figure 11. Capacitance Characteristics

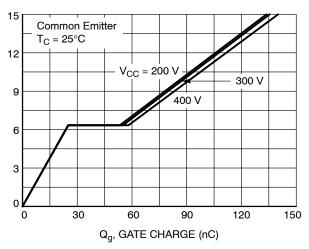


Figure 12. Gate Charge Characteristic (Tc = 25°C)

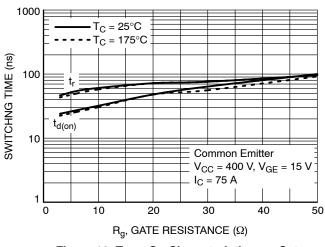


Figure 13. Turn-On Characteristics vs. Gate Resistance

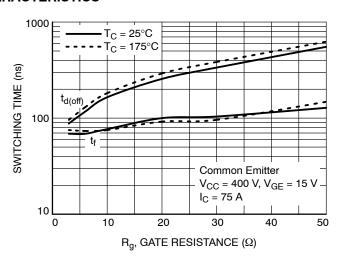


Figure 14. Turn-Off Characteristics vs. Gate Resistance

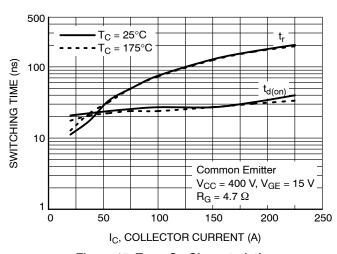


Figure 15. Turn-On Characteristics vs. Collector Current

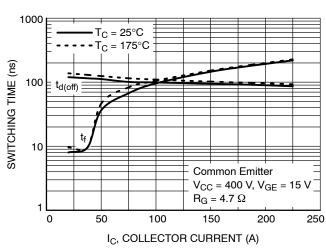


Figure 16. Turn-Off Characteristics vs.
Collector Current

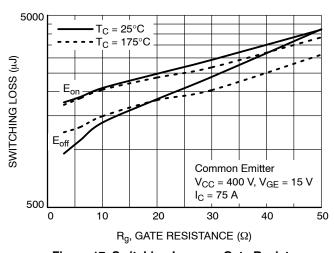


Figure 17. Switching Loss vs. Gate Resistance

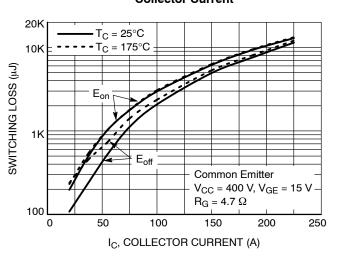


Figure 18. Switching Loss vs. Collector Current

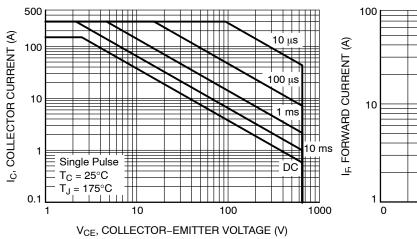


Figure 19. SOA Characteristics (FBSOA)

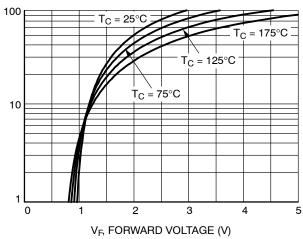


Figure 20. (Diode) Forward Characteristics vs. (Normal I-V)

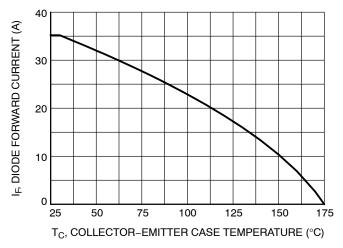


Figure 21. (Diode) Forward Current Derating

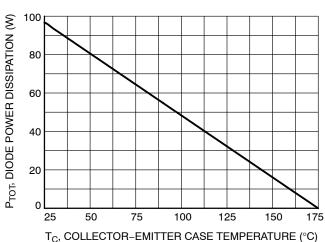


Figure 22. (Diode) Power Derating

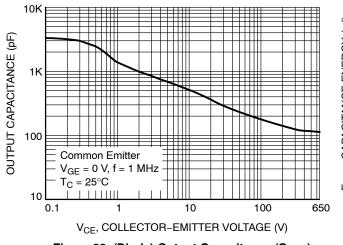


Figure 23. (Diode) Output Capacitance (Coes) vs. Reverse Voltage

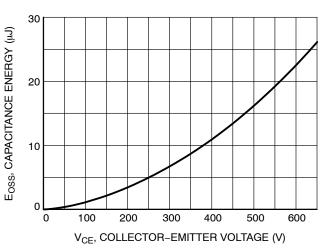


Figure 24. (Diode) Output Capacitance Stored Energy

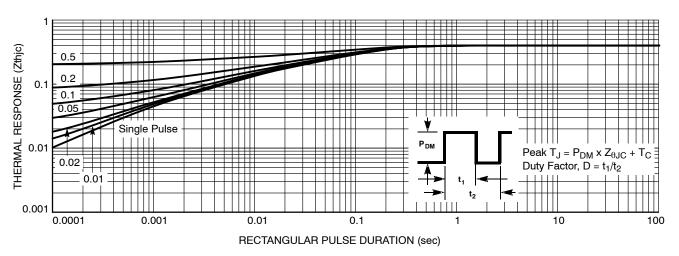


Figure 25. Transient Thermal Impedance of IGBT

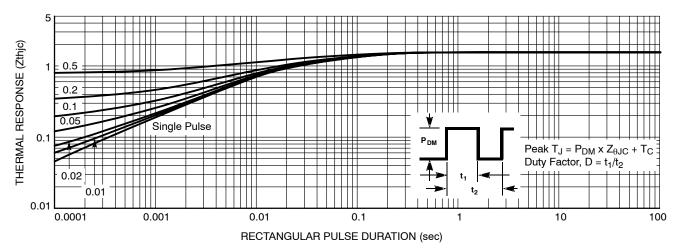
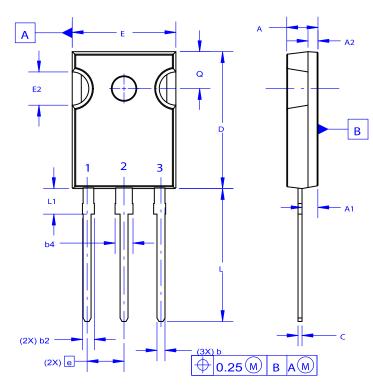


Figure 26. Transient Thermal Impedance of Diode

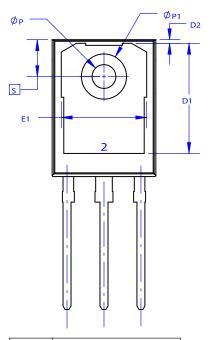
PACKAGE DIMENSIONS

TO-247-3LD CASE 340CX ISSUE O



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.



DIM	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	4.58	4.70	4.82	
A1	2.20	2.40	2.60	
A2	1.40	1.50	1.60	
D	20.32	20.57	20.82	
Е	15.37	15.62	15.87	
E2	4.96	5.08	5.20	
е	?	5.56	?	
L	19.75	20.00	20.25	
L1	3.69	3.81	3.93	
ØР	3.51	3.58	3.65	
Q	5.34	5.46	5.58	
S	5.34	5.46	5.58	
b	1.17	1.26	1.35	
b2	1.53	1.65	1.77	
b4	2.42	2.54	2.66	
С	0.51	0.61	0.71	
D1	13.08	~	~	
D2	0.51	0.93	1.35	
E1	12.81	~	~	
ØP1	6.60	6.80	7.00	

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